

IRMTOUCH INC.

IR Multi-Point TOUCH FRAME

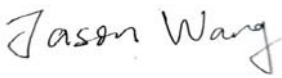
Model: TII70-XX-N
Serial Model: See P5

November 12, 2013
Report No.: 13020703-FCC-E
(This report supersedes NONE)



Modifications made to the product : None

This Test Report is Issued Under the Authority of:

		
Jason Wang Compliance Engineer	Alex Liu Technical Manager	

EMC Test Report

To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4: 2009

SIEMIC, INC.
Accessing global markets



Laboratory Introduction

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Accreditations for Conformity Assessment

Country/Region	Accreditation Body	Scope
USA	FCC, A2LA	EMC, RF/Wireless, Telecom
Canada	IC, A2LA, NIST	EMC, RF/Wireless, Telecom
Taiwan	BSMI, NCC , NIST	EMC, RF, Telecom, Safety
Hong Kong	OFTA, NIST	RF/Wireless, Telecom
Australia	NATA, NIST	EMC, RF, Telecom, Safety
Korea	KCC/RRA, NIST	EMI, EMS, RF, Telecom, Safety
Japan	VCCI, JATE, TELEC, RFT	EMI, RF/Wireless, Telecom
Mexico	NOM, COFETEL, Caniety	Safety, EMC, RF/Wireless, Telecom
Europe	A2LA, NIST	EMC, RF, Telecom, Safety

Accreditations for Product Certifications

Country/Region	Accreditation Body	Scope
USA	FCC TCB, NIST	EMC, RF, Telecom
Canada	IC FCB, NIST	EMC, RF, Telecom
Singapore	iDA, NIST	EMC, RF, Telecom
EU	NB	EMC & R&TTE Directive
Japan	MIC, (RCB 208)	RF, Telecom
Hong Kong	OFTA (US002)	RF, Telecom

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CONTENTS

1

EXECUTIVE SUMMARY & EUT INFORMATION

5

2

TECHNICAL DETAILS

6

3

MODIFICATION.....

7

4

TEST SUMMARY.....

8

5

MEASUREMENTS, EXAMINATION AND DERIVED RESULTS

9

ANNEX A.

TEST INSTRUMENTATION & METHOD

14

ANNEX B.

EUT AND TEST SETUP PHOTOGRAPHS

18

ANNEX C.

TEST SETUP AND SUPPORTING EQUIPMENT.....

34

ANNEX D.

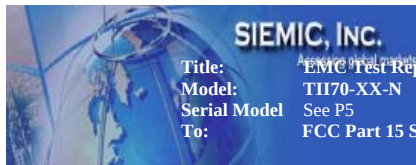
USER MANUAL / BLOCK DIAGRAM / SCHEMATICS / PART LIST

38

ANNEX E.

DECLARATION OF SIMILARITY

39



Title: EMC Test Report for IR Multi-Point TOUCH FRAME
Model: TII70-XX-N
Serial Model: See P5
To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

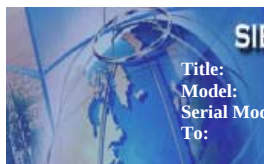
Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 5 of 40
www.siemic.com.cn

1 EXECUTIVE SUMMARY & EUT INFORMATION

The purpose of this test programme was to demonstrate compliance of the IRMTOUCH INC., IR Multi-Point TOUCH FRAME and Model: TII70-XX-N against the current Stipulated Standards. The IR Multi-Point TOUCH FRAME has demonstrated compliance with the FCC Part 15 Subpart B Class B: 2013.

EUT Information

EUT
Description : IR Multi-Point TOUCH FRAME
Model : TII70-XX-N
Serial Model : TII65-XX-N, TII60-XX-N, TII55-XX-N, TII52-XX-N TII47-XX-N,
TII46-XX-N, TII42-XX-N, TII37-XX-N, TII32-XX-N
Input Power : DC 5V By USB Power Supply
Classification
Per Stipulated : Class B Emission Product Per
Test Standard : FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

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Serial Model: See P5
To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 6 of 40
www.siemic.com.cn

2 TECHNICAL DETAILS

Purpose	Compliance testing of IR Multi-Point TOUCH FRAME with stipulated standards
Applicant / Client	IRMTouch INC. Building 5, No 445 Humin Road, Minhang, Shanghai, China
Manufacturer	IRMTouch INC. Building 5, No 445 Humin Road, Minhang, Shanghai, China
Laboratory performing the tests	SIEMIC (Nanjing-China) Laboratories NO.2-1, Longcang Dadao, Yuhua Economic Development Zone, Nanjing, China Tel: +86(25)86730128/86730129 Fax: +86(25)86730127 Email: China@siemic.com.cn
Test report reference number	13020703-FCC-E
Date EUT received	7th August, 2013
Standard applied	FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009
Dates of test (from – to)	27th August to 28th August, 2013
No of Units	#1
Equipment Category	Class B Emission Product
Trade Name	IRMT
Highest Operated Frequency(ies)	8MHz
Port/Connectors	USB Port
FCC ID	2AASUIRMTTII



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Model: TH70-XX-N
Serial Model: See P5
To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 7 of 40
www.siemic.com.cn

3 MODIFICATION

NONE

4 TEST SUMMARY

The product was tested in accordance with the following specifications.
All testing has been performed according to below product classification:

Class B Emission Product

Test Results Summary

Emissions			
Test Standard	Description	Product Class	Pass / Fail
FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009	Conducted Emissions	See Above	Pass
FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009	Radiated Emissions	See Above	Pass

All measurement uncertainty is not taken into consideration for all presented test result.

5 MEASUREMENTS, EXAMINATION AND DERIVED RESULTS

5.1 Conducted Emissions Test Results

Note:

1. All possible modes of operation were investigated. Only the several worst case emissions measured, using the correct CISPR and Average detectors, are reported. All other emissions were relatively insignificant.
2. A "-ve" margin indicates a PASS as it refers to the margin present below the limit line at the particular frequency.
3. Conducted Emissions Measurement Uncertainty
All test measurements carried out are traceable to national standards. The uncertainty of the measurement at a confidence level of approximately 95% (in the case where distributions are normal), with a coverage factor of 2, in the range 9kHz – 30MHz (Average & Quasi-peak) is $\pm 3.86\text{dB}$.
4. Environmental Conditions

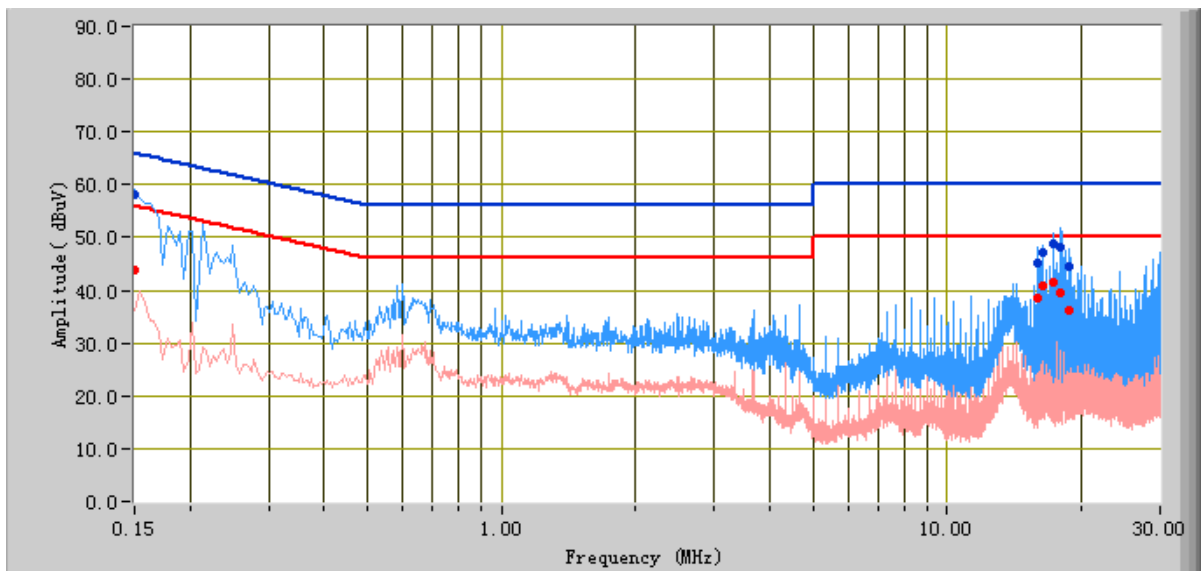
Temperature	25°C
Relative Humidity	65%
Atmospheric Pressure	995mbar
5. Test Date : 27th August, 2013
Tested By : Jason Wang

Test Result: Pass

Test Mode:	Normal Working
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Peak Detector Quasi Peak Limit

Average Detector Average Limit

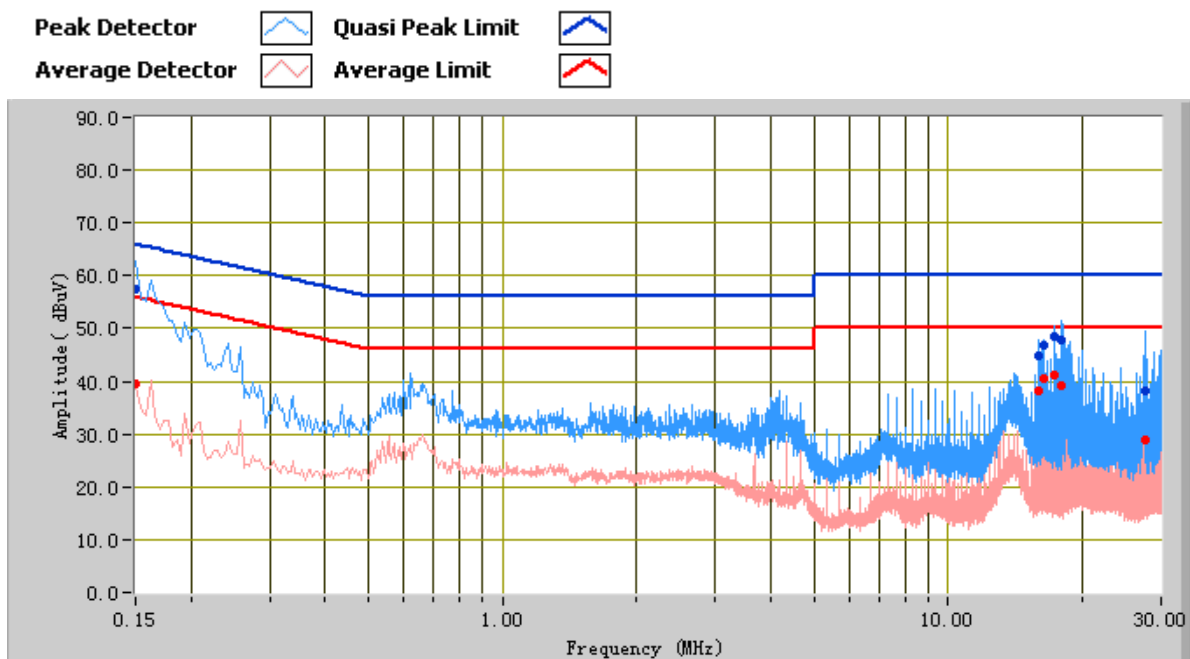


Test Data

Phase Line Plot at 120Vac, 60Hz

Frequency (MHz)	Quasi Peak (dBμV)	Limit (dBμV)	Margin (dB)	Average (dBμV)	Limit (dBμV)	Margin (dB)	Factors (dB)
0.15	58.22	66.00	-7.78	43.72	56.00	-12.28	12.22
18.00	48.02	60.00	-11.98	39.50	50.00	-10.50	11.49
17.33	48.67	60.00	-11.33	41.56	50.00	-8.44	11.47
16.33	47.07	60.00	-12.93	40.87	50.00	-9.13	11.45
16.00	45.12	60.00	-14.88	38.56	50.00	-11.44	11.44
18.66	44.63	60.00	-15.37	36.27	50.00	-13.73	11.51

Test Mode:	Normal Working
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Test Data

Phase Neutral Plot at 120Vac, 60Hz

Frequency (MHz)	Quasi Peak (dBμV)	Limit (dBμV)	Margin (dB)	Average (dBμV)	Limit (dBμV)	Margin (dB)	Factors (dB)
0.15	57.43	66.00	-8.57	39.67	56.00	-16.33	12.21
18.00	47.67	60.00	-12.33	39.24	50.00	-10.76	11.50
17.33	48.44	60.00	-11.56	41.24	50.00	-8.76	11.48
27.66	38.03	60.00	-21.97	28.76	50.00	-21.24	11.82
16.33	46.67	60.00	-13.33	40.48	50.00	-9.52	11.44
16.00	44.86	60.00	-15.14	38.20	50.00	-11.80	11.43

5.2 Radiated Emissions Test Results

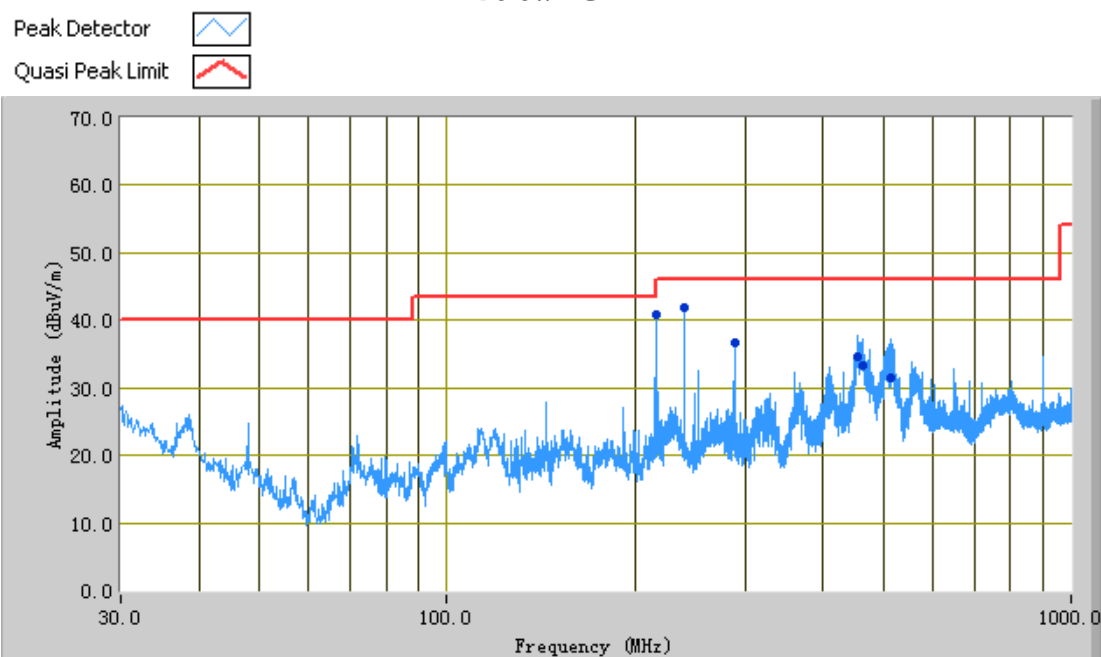
Note:

1. All possible modes of operation were investigated. Only the 6 worst case emissions measured, using the correct CISPR detectors, are reported. All other emissions were relatively insignificant.
2. A "-ve" margin indicates a PASS as it refers to the margin present below the limit line at the particular frequency.
3. **Radiated Emissions Measurement Uncertainty**
All test measurements carried out are traceable to national standards. The uncertainty of the measurement at a confidence level of approximately 95% (in the case where distributions are normal), with a coverage factor of 2, in the range 30MHz – 1GHz (QP only @ 3m & 10m) is +6dB/-6dB (for EUTs < 0.5m X 0.5m X 0.5m).
4. Environmental Conditions Temperature 25°C
Relative Humidity 60%
Atmospheric Pressure 998mbar
5. Test Date: 28th August, 2013
Tested By: Jason Wang

Test Result: Pass

Test Mode:	Normal Working
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Below 1GHz



Test Data

Vertical& Horizontal Polarity Plot at 3m

Frequency (MHz)	Peak (dBμV/m)	Azimuth	Polarity (H/V)	Height (cm)	Factors (dB)	Limit (dBμV/m)	Margin (dB)
239.99	41.87	338.00	H	146.00	-32.40	46.00	-4.13
216.42	40.96	132.00	H	153.00	-33.35	46.00	-5.04
454.45	34.62	242.00	V	110.00	-29.13	46.00	-11.38
463.96	33.22	241.00	V	101.00	-29.03	46.00	-12.78
514.16	31.53	18.00	H	253.00	-28.45	46.00	-14.47
239.99	41.87	338.00	H	146.00	-32.40	46.00	-4.13

Note: the highest frequency of the internal sources of the EUT is less than 108MHz, so the measurement shall only be made up to 1GHz.

Annex A. TEST INSTRUMENTATION & METHOD

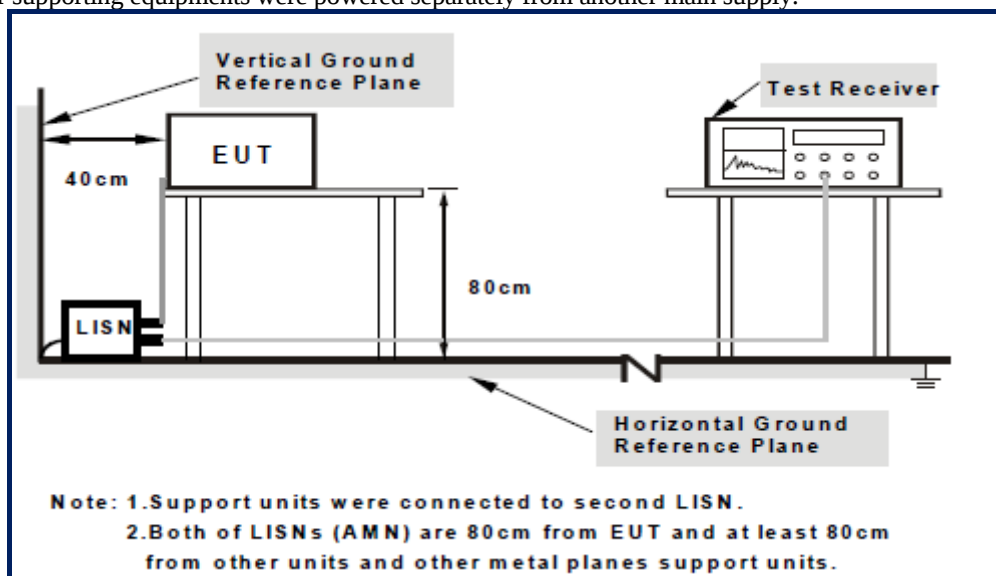
Annex A.i. TEST INSTRUMENTATION & GENERAL PROCEDURES

Instrument	Model	Serial #	Calibration Date	Calibration Due Date
AC Line Conducted Emissions				
R&S EMI Test Receiver	ESPI3	101216	09/27/2012	09/26/2013
ROHDE&SCHWARZ V-LISN	ESH3-Z5	838979/005	09/27/2012	09/26/2013
Com-Power Transient Limiter	LIT-153	531021	09/27/2012	09/26/2013
SIEMIC Labview Conducted Emissions software	V1.0	N/A	N/A	N/A
Radiated Emissions				
Hp Spectrum Analyzer	8563E	3821A09023	09/27/2012	09/26/2013
R&S EMI Receiver	ESPI3	101216	09/27/2012	09/26/2013
Antenna (30MHz~6GHz)	JB6	A121411	03/27/2013	03/26/2014
ETS-Lindgren Antenna (1 ~18GHz)	3115	N/A	10/27/2012	10/26/2013
A-INFOMW Antenna (1 ~18GHz)	JXTXLB-10180	J2031081120092	10/09/2012	10/08/2013
Horn Antenna (18~40GHz)	AH-840	101013	09/27/2012	09/26/2013
Microwave Pre-Amp (18~40GHz)	PA-840	181250	09/27/2012	09/26/2013
Hp Agilent Pre-Amplifier	8447F	1937A01160	10/27/2012	10/26/2013
MITEQ Pre-Amplifier (0.1 ~ 18GHz)	AMF-7D-00101800-30-10P	1451709	10/27/2012	10/26/2013
Chamber	3m	N/A	04/13/2013	04/12/2014
SIEMIC Labview Radiated Emissions software	V1.0	N/A	N/A	N/A

Annex A.ii. CONDUCTED EMISSIONS TEST DESCRIPTION

Test Set-up

1. The EUT and supporting equipment were set up in accordance with the requirements of the standard on top of a 1.5m x 1m x 0.8m high, non-metallic table, as shown in Annex B.
2. The power supply for the EUT was fed through a 50Ω/50μH EUT LISN, connected to filtered mains.
3. The RF OUT of the EUT LISN was connected to the EMI test receiver via a low-loss coaxial cable.
4. All other supporting equipments were powered separately from another main supply.



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration1

Test Method

1. The EUT was switched on and allowed to warm up to its normal operating condition.
2. A scan was made on the NEUTRAL line (for AC mains) or Earth line (for DC power) over the required frequency range using an EMI test receiver.
3. High peaks, relative to the limit line, were then selected.
4. The EMI test receiver was then tuned to the selected frequencies and the necessary measurements made with a receiver bandwidth setting of 10kHz. For FCC tests, only Quasi-peak measurements were made; while for CISPR/EN tests, both Quasi-peak and Average measurements were made.
5. Steps 2 to 4 were then repeated for the LIVE line (for AC mains) or DC line (for DC power).

Sample Calculation Example

At 20MHz	limit = 250μV = 47.96dBμV
Transducer factor of LISN, pulse limiter & cable loss at 20MHz = 11.20dB	
Q-P reading obtained directly from EMI Receiver = 40.00dBμV (Calibrated for system losses)	
Therefore, Q-P margin = 40.00-47.96 = -7.96	i.e. 7.96 dB below limit

Annex A.iii. RADIATED EMISSIONS TEST DESCRIPTION

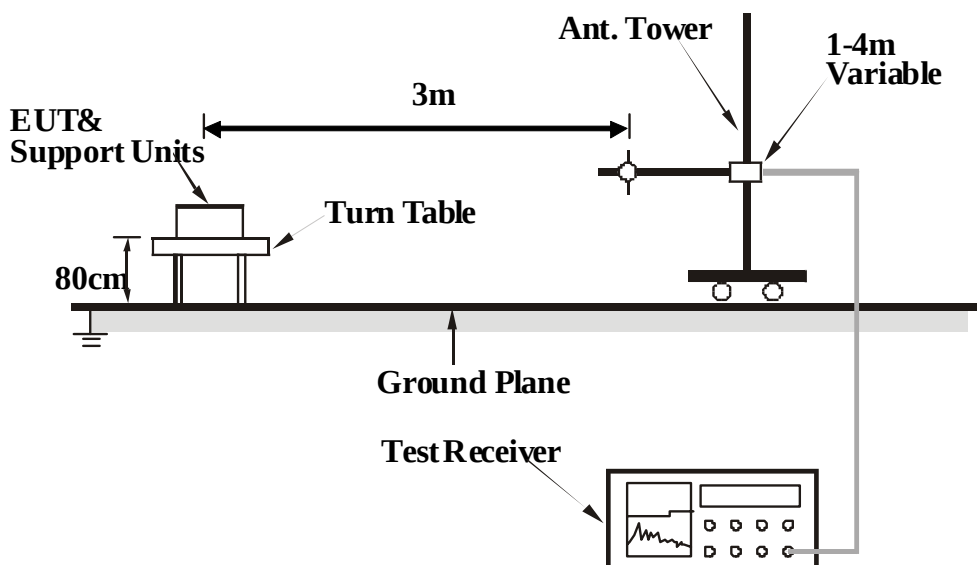
EUT Characterisation

EUT characterisation, over the frequency range from 30MHz to 10th Harmonic, was done in order to minimise radiated emissions testing time while still maintaining high confidence in the test results.

The EUT was placed in the chamber, at a height of about 0.8 m on a turntable. Its radiated emissions frequency profile was observed, using a spectrum analyzer /receiver with the appropriate broadband antenna placed 3m away from the EUT. Radiated emissions from the EUT were maximised by rotating the turntable manually, changing the antenna polarisation and manipulating the EUT cables while observing the frequency profile on the spectrum analyzer / receiver. Frequency points at which maximum emissions occurred; clock frequencies and operating frequencies were then noted for the formal radiated emissions test at the Open Area Test Site (OATS) or 3m EMC chamber.

Test Set-up

1. The EUT and supporting equipment were set up in accordance with the requirements of the standard on top of a 1.5mX1.0mX0.8m high, non-metallic table.
2. The filtered power supply for the EUT and supporting equipment were tapped from the appropriate power sockets located on the turntable.
3. The relevant broadband antenna was set at the required test distance away from the EUT and supporting equipment boundary.



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration2

Test Method

The following procedure was performed to determine the maximum emission axis of EUT:

1. With the receiving antenna is H polarization, rotate the EUT in turns with three orthogonal axes to determine the axis of maximum emission.
2. With the receiving antenna is V polarization, rotate the EUT in turns with three orthogonal axes to determine the axis of maximum emission.
3. Compare the results derived from above two steps. So, the axis of maximum emission from EUT was determined and the configuration was used to perform the final measurement.

Final Radiated Emission Measurement

1. Setup the configuration according to figure 1. Turn on EUT and make sure that it is in normal function.
2. For emission frequencies measured below 1GHz, a pre-scan is performed in a shielded chamber to determine the accurate frequencies of higher emissions will be checked on an open test site. As the same purpose, for emission frequencies measured above 1GHz, a pre-scan also be performed with a 1 meter measuring distance before final test.
3. For emission frequencies measured below and above 1GHz, set the spectrum analyzer on a 100kHz and 1MHz resolution bandwidth respectively for each frequency measured in step 2.
4. The search antenna is to be raised and lowered over a range from 1 to 4 meters in horizontally polarized orientation. Position the highness when the highest value is indicated on spectrum analyzer, then change the orientation of EUT on test table over a range from 0° to 360° with a speed as slow as possible, and keep the azimuth that highest emission is indicated on the spectrum analyzer. Vary the antenna position again and record the highest value as a final reading.
5. Repeat step 4 until all frequencies need to be measured was complete.
6. Repeat step 5 with search antenna in vertical polarized orientations.

During the radiated emission test, the Spectrum Analyzer was set with the following configurations:

Frequency Band (MHz)	Function	Resolution bandwidth	Video Bandwidth
30 to 1000	Peak	100kHz	100kHz
Above 1000	Peak	1MHz	1MHz
	Average	1MHz	10Hz

Sample Calculation Example

The field strength is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain (if any) from the measured reading. For the limit is employed average value, therefore the peak value can be transferred to average value by subtracting the duty factor. The basic equation with a sample calculation is as follows:

$$\text{Peak} = \text{Reading} + \text{Corrected Factor}$$

where

Corr. Factor = Antenna Factor + Cable Factor - Amplifier Gain (if any)

And the average value is

$$\text{Average} = \text{Peak Value} + \text{Duty Factor or}$$

$$\text{Set RBW} = 1\text{MHz}, \text{VBW} = 10\text{Hz}.$$

Note:

If the measured frequencies are fall in the restricted frequency band, the limit employed must be quasi peak value when frequencies are below or equal to 1GHz. And the measuring instrument is set to quasi peak detector function.



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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 18 of 40
www.siemic.com.cn

Annex B. EUT AND TEST SETUP PHOTOGRAPHS

Annex B.i. Photograph 1: EUT External Photo



EUT - Front View



EUT – Rear View



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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 19 of 40
www.siemic.com.cn



EUT – Top View



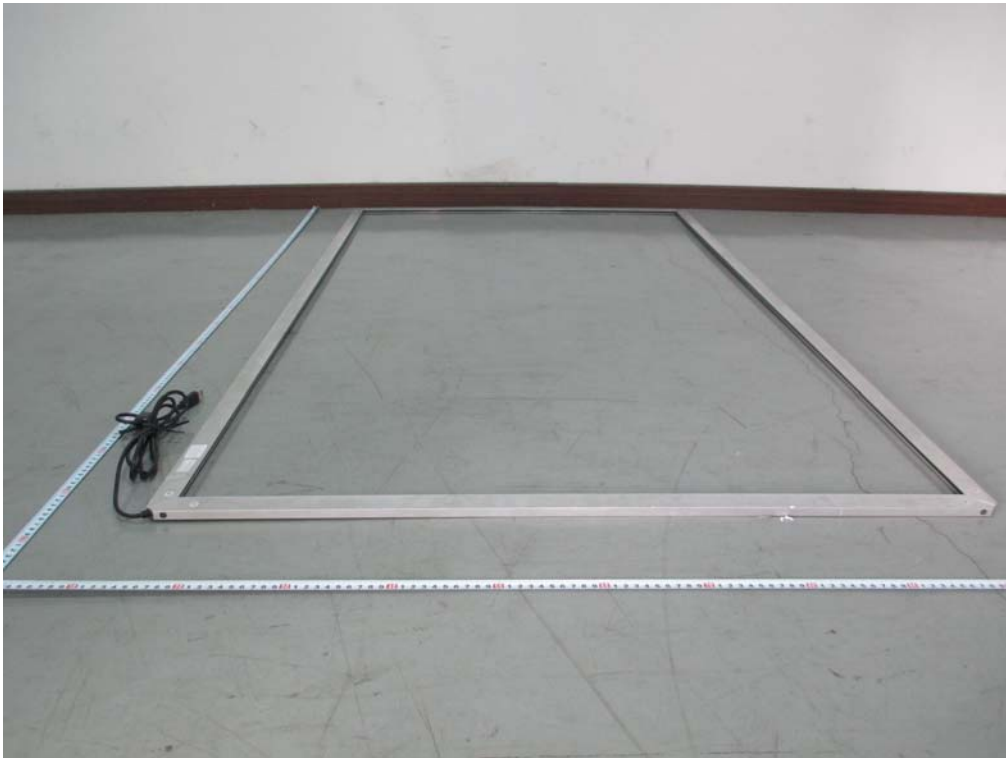
EUT – Bottom View



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Serial Model: See P5
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 20 of 40
www.siemic.com.cn



EUT – Left View



EUT – Right View



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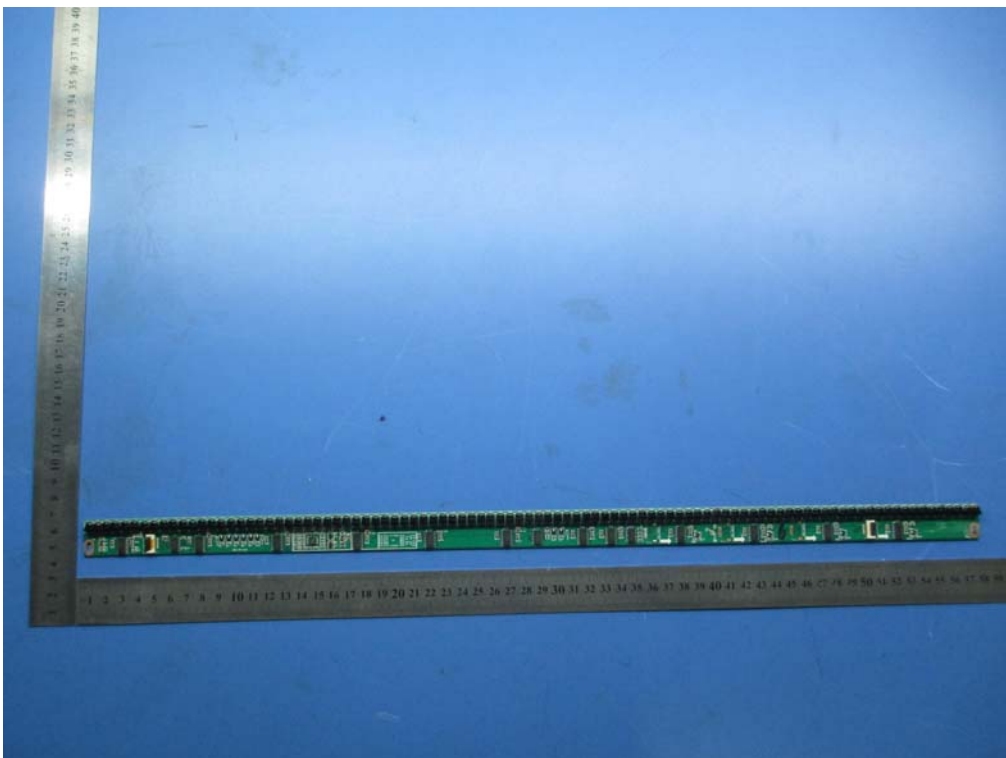
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To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 21 of 40
www.siemic.com.cn

Annex B.ii. Photograph 2: EUT Internal Photo



EUT – Uncover Front View



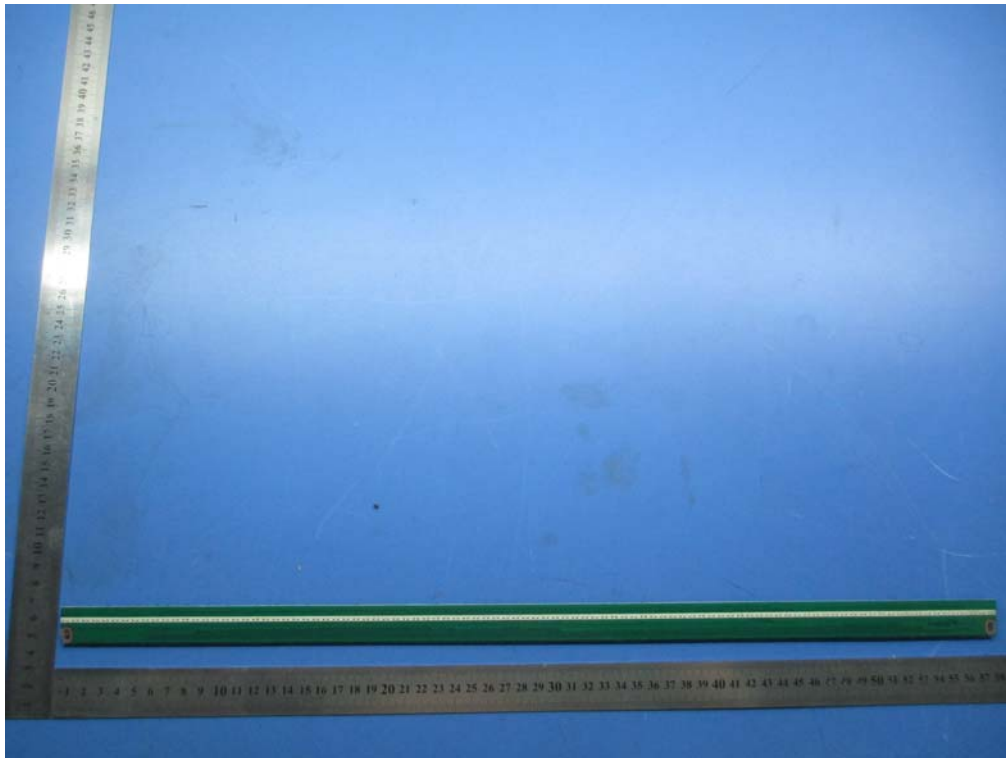
EUT PCB Board1 - Front View



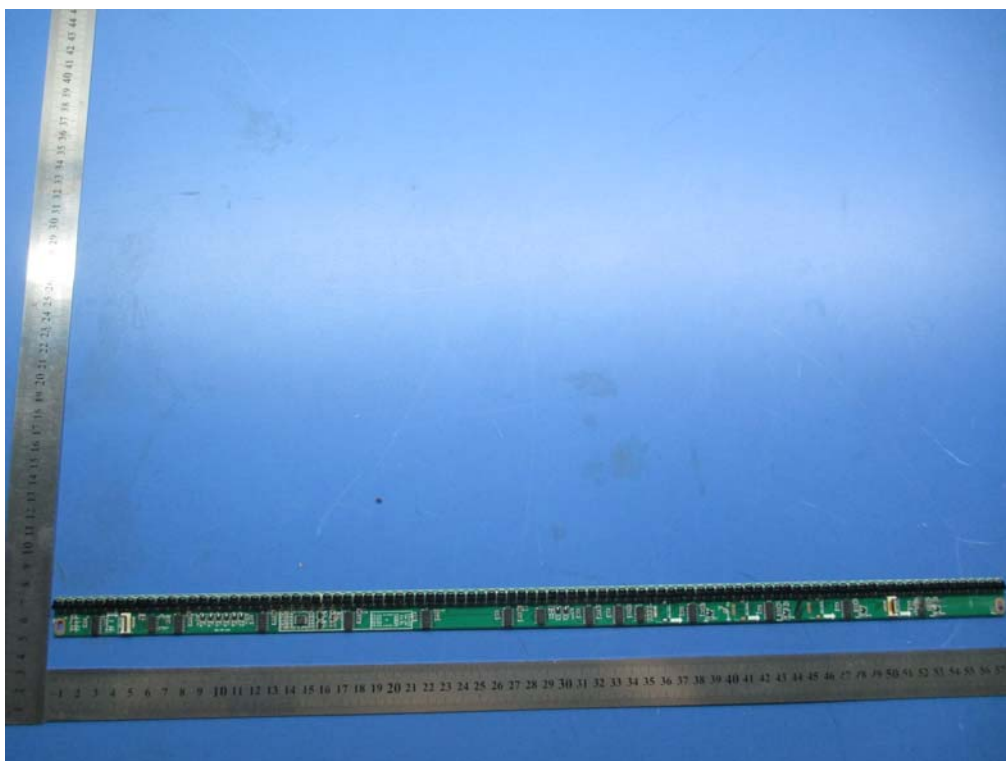
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 22 of 40
www.siemic.com.cn



EUT PCB Board1 - Rear View



EUT PCB Board 2 - Front View



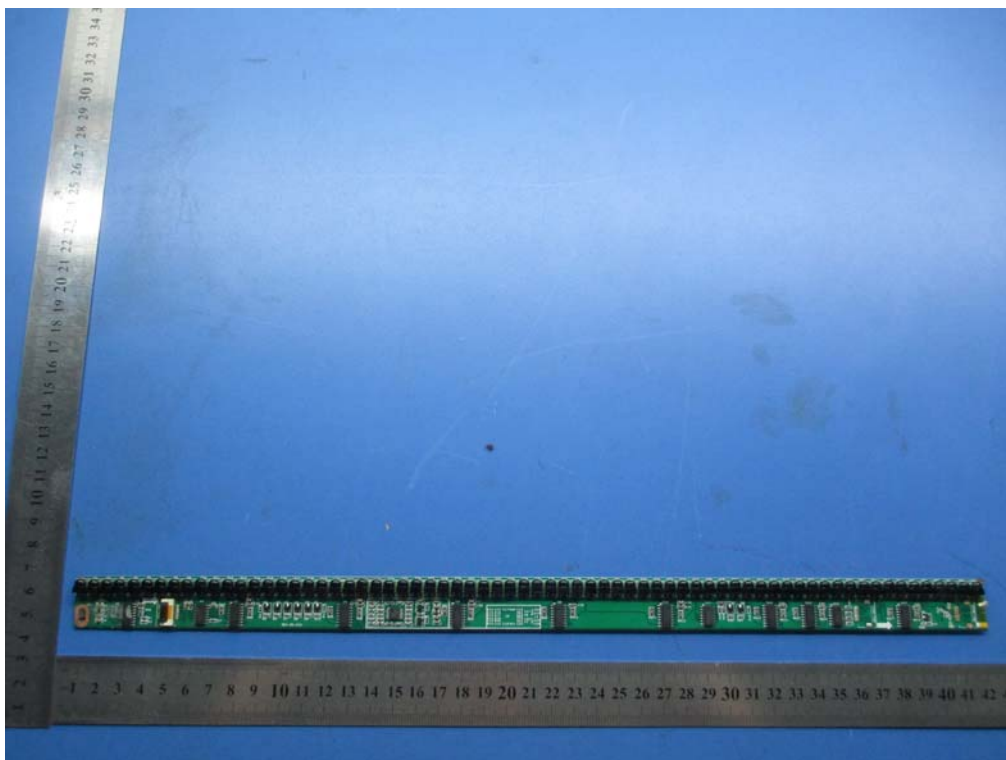
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 23 of 40
www.siemic.com.cn



EUT PCB Board 2 - Rear View



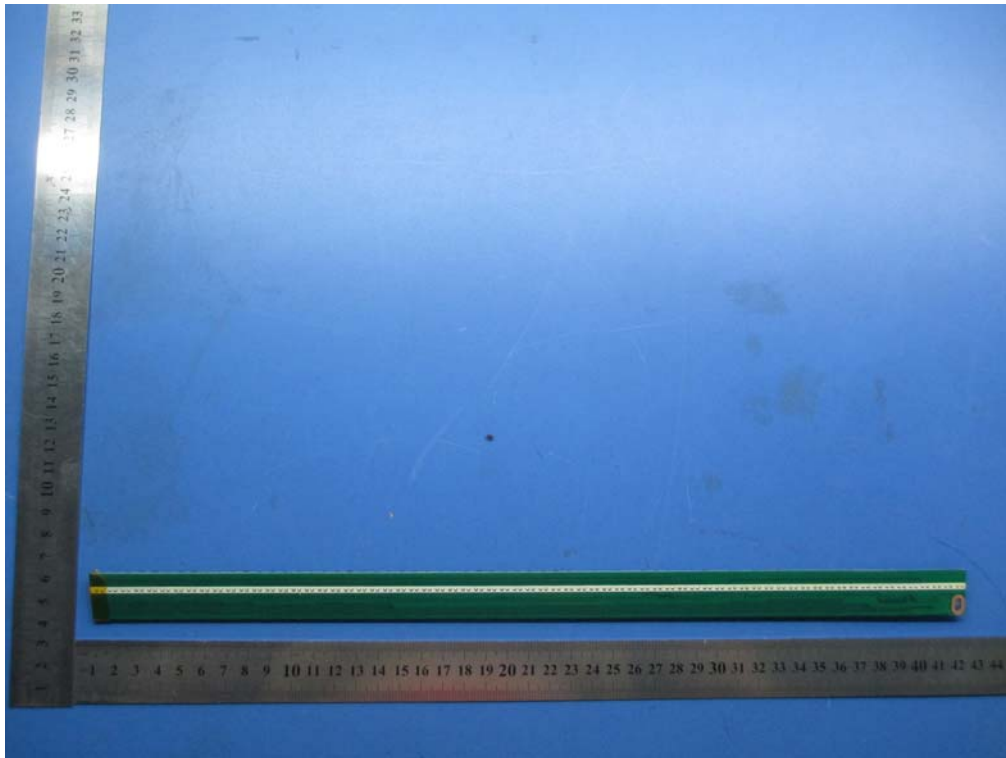
EUT PCB Board 3 - Front View



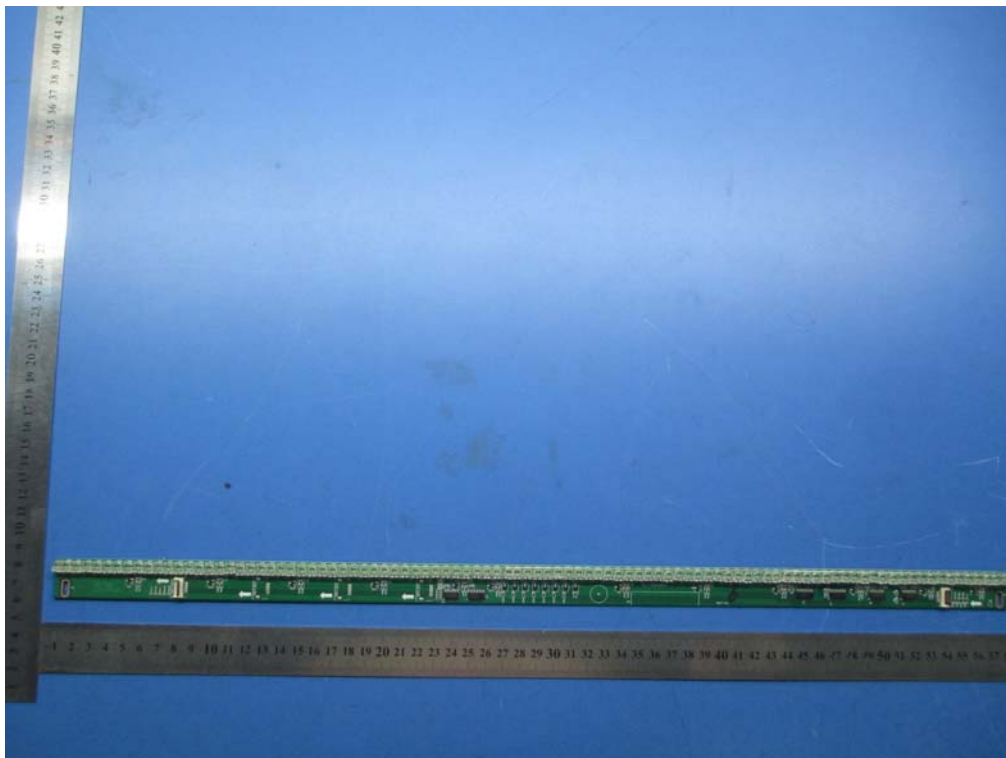
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 24 of 40
www.siemic.com.cn



EUT PCB Board 3 - Rear View



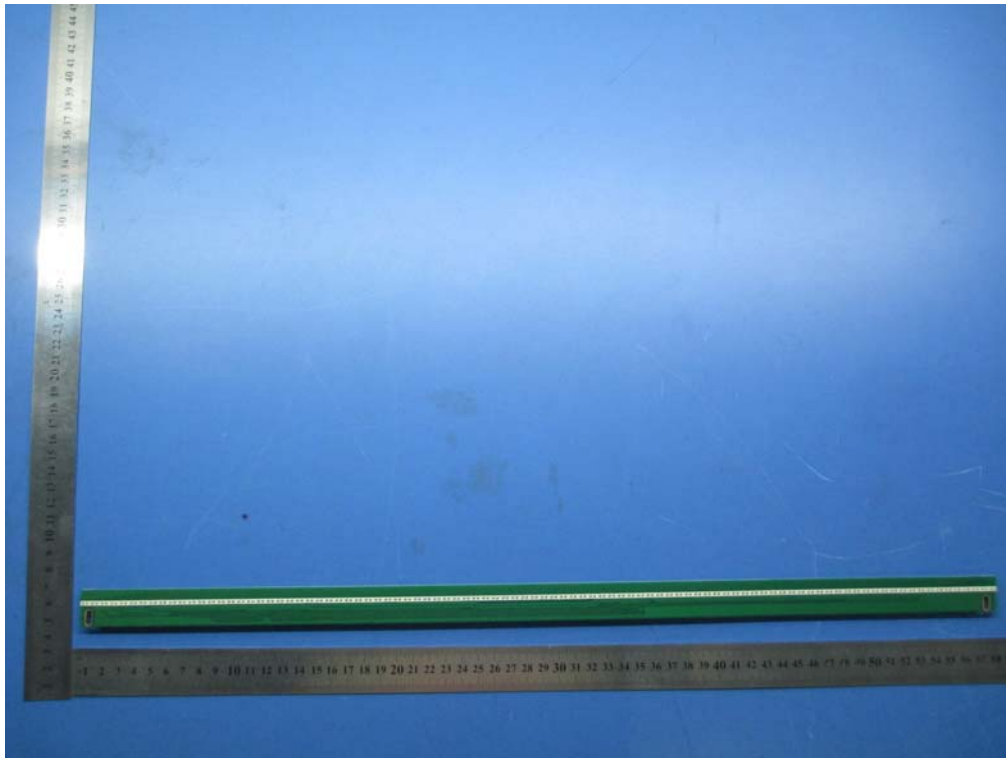
EUT PCB Board 4 - Front View



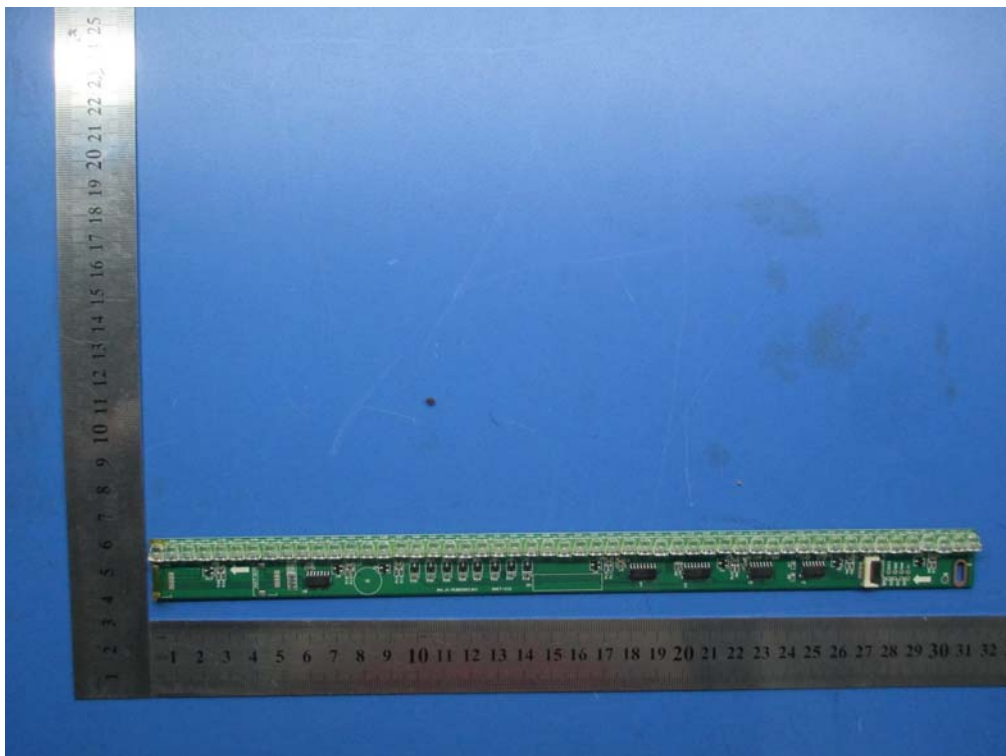
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 25 of 40
www.siemic.com.cn



EUT PCB Board 4 - Rear View



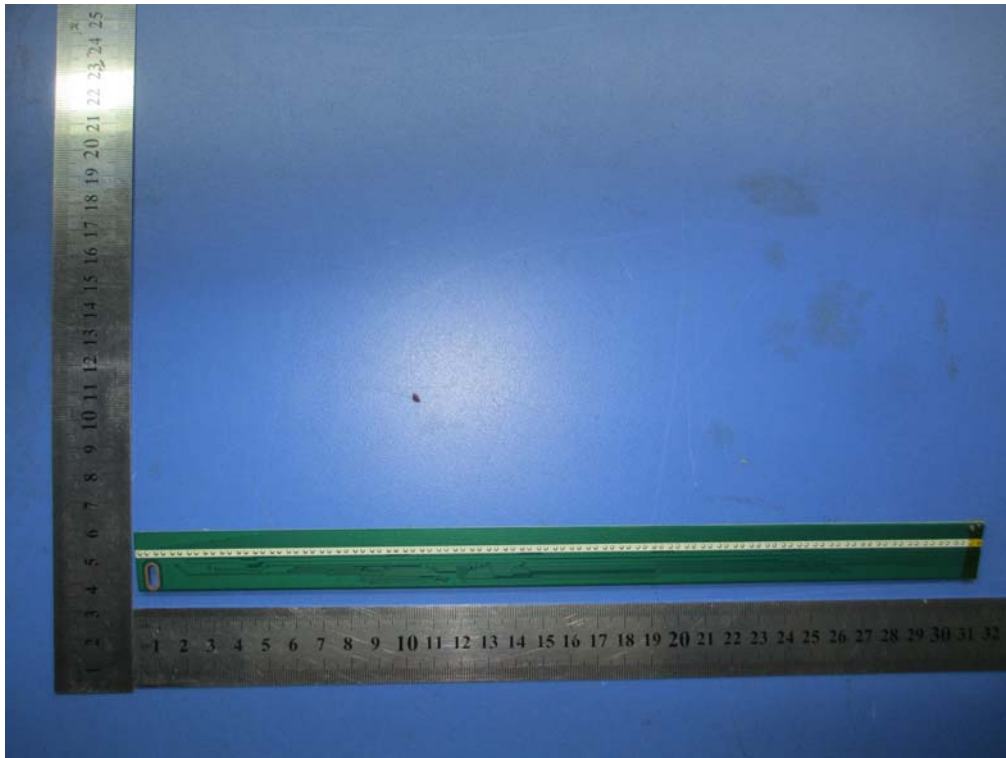
EUT PCB Board 5 - Front View



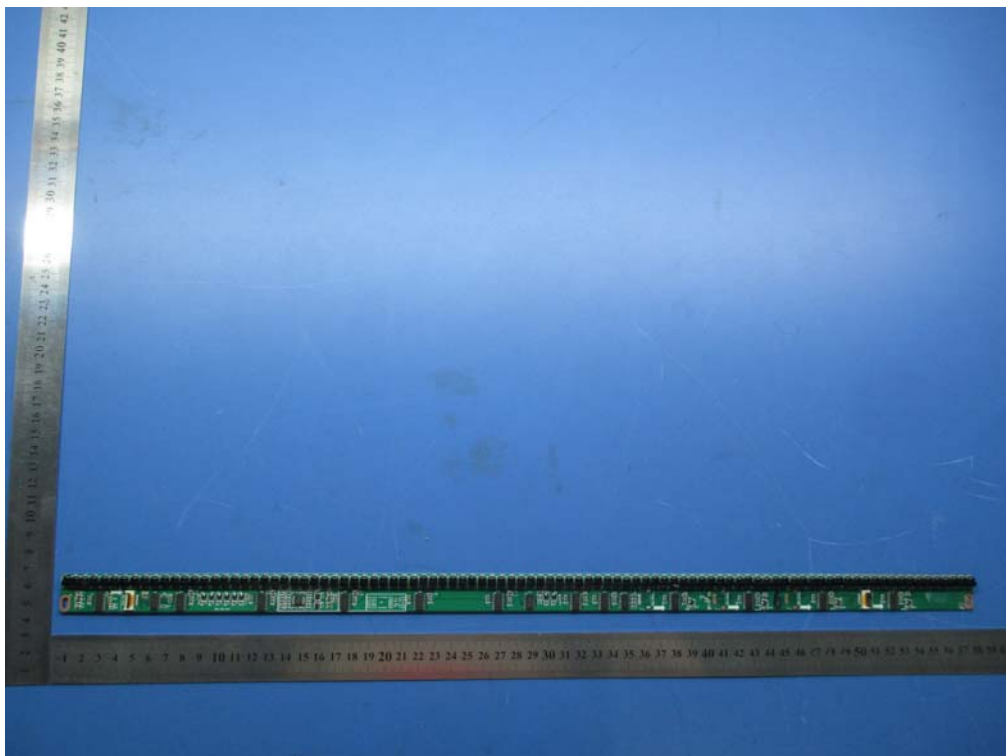
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 26 of 40
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EUT PCB Board 5 - Rear View



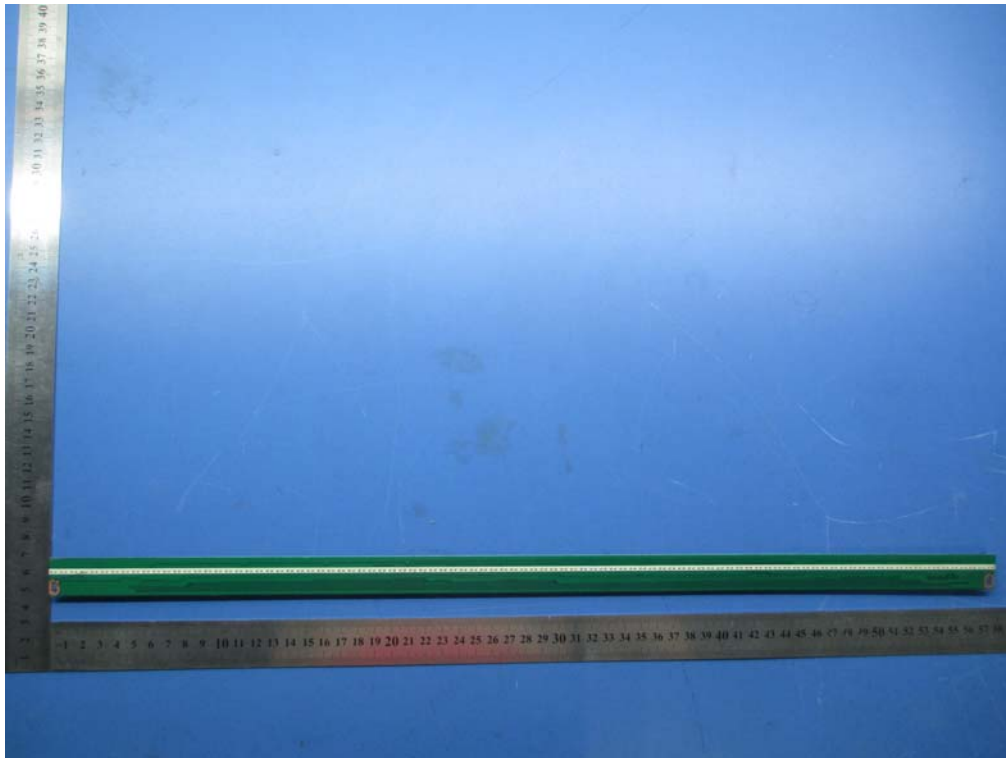
EUT PCB Board 6 - Front View



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Serial Model: See P5
To: FCC Part 15 Subpart B Class B: 2013, ANSI C63.4:2009

Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 27 of 40
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EUT PCB Board 6 - Rear View



EUT PCB Board 7 - Front View



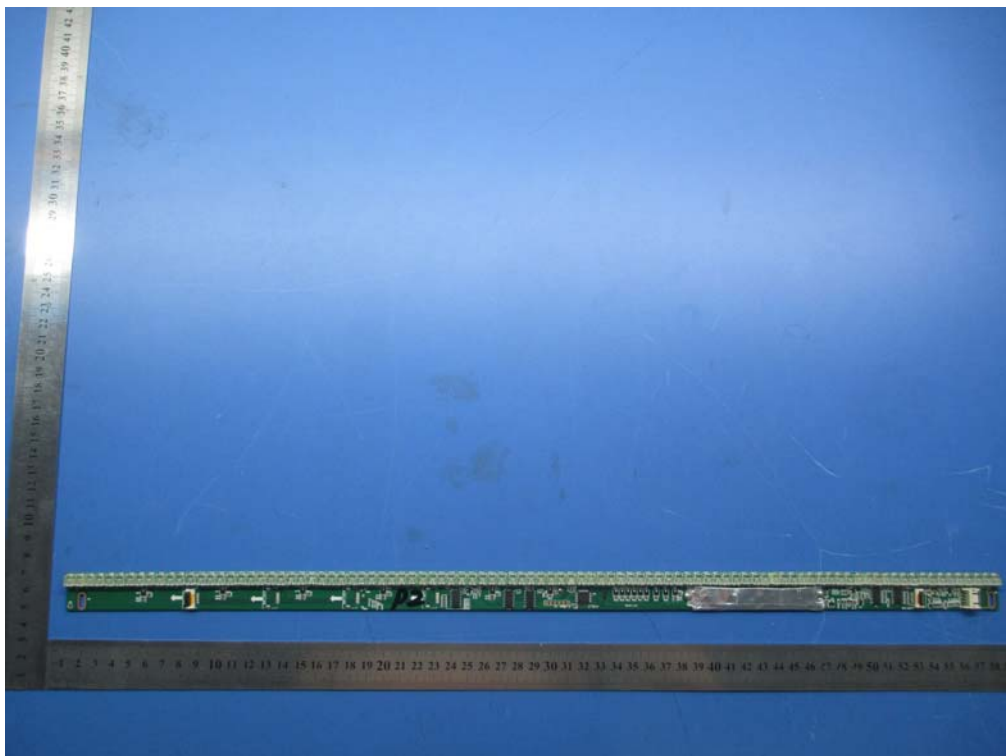
SIEMIC, INC.

Title: EMC Test Report for IR Multi-Point TOUCH FRAME
Model: TII70-XX-N
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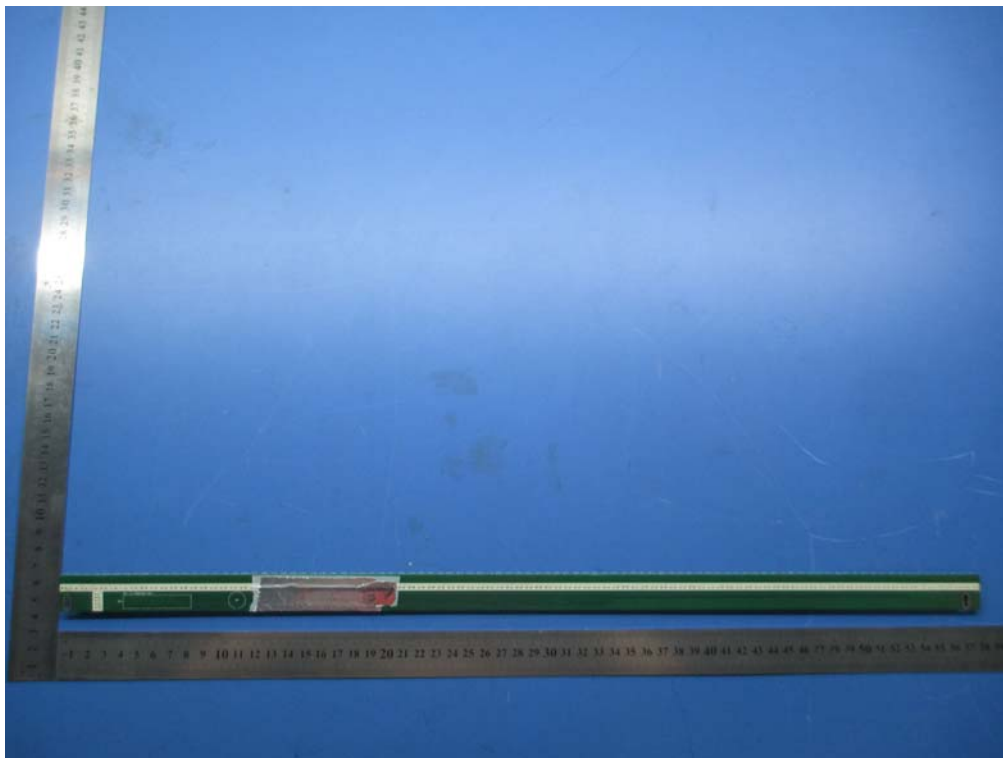
Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 28 of 40
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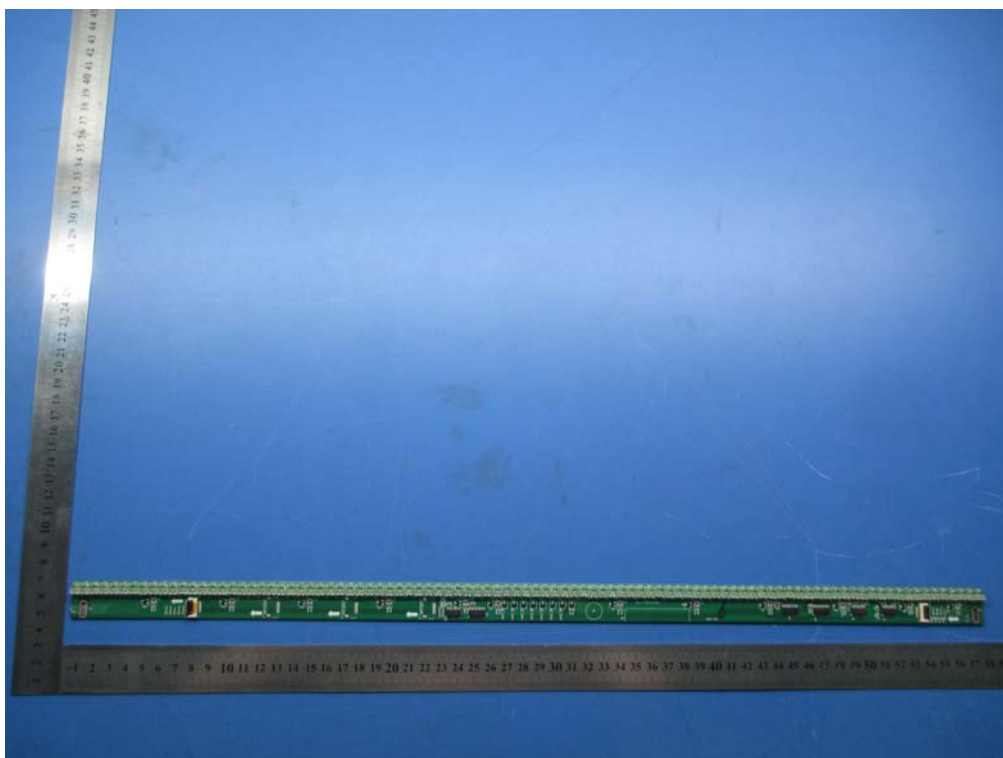
EUT PCB Board 7 - Rear View



EUT PCB Board 8- Front View



EUT PCB Board 8 - Rear View



EUT PCB Board 9- Front View



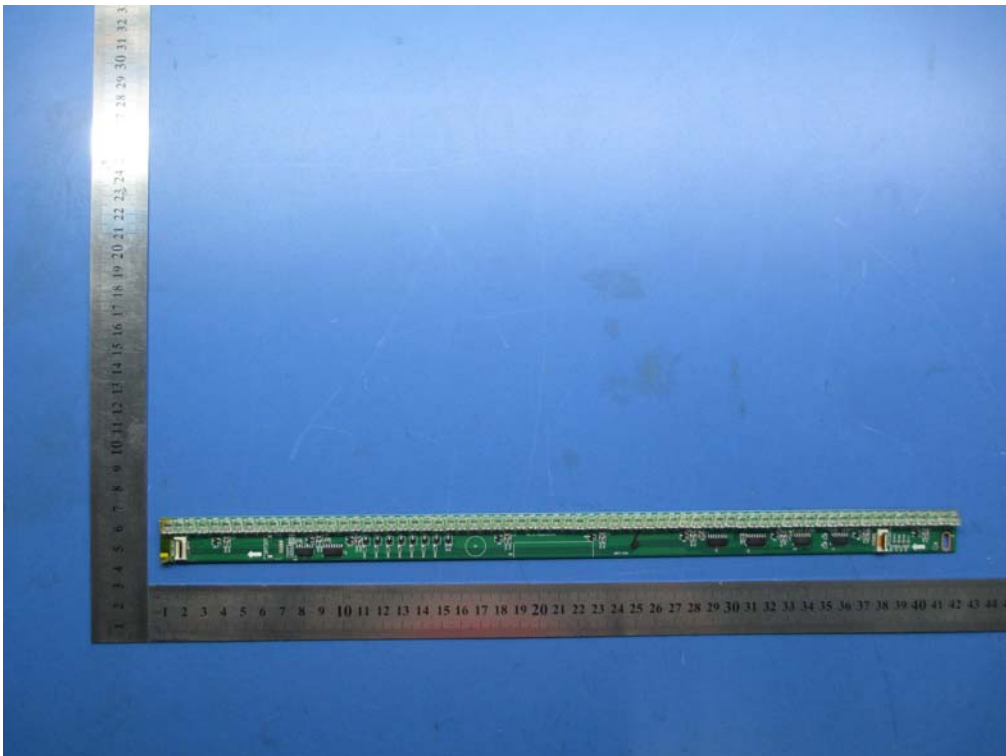
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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 30 of 40
www.siemic.com.cn



EUT PCB Board 9 - Rear View



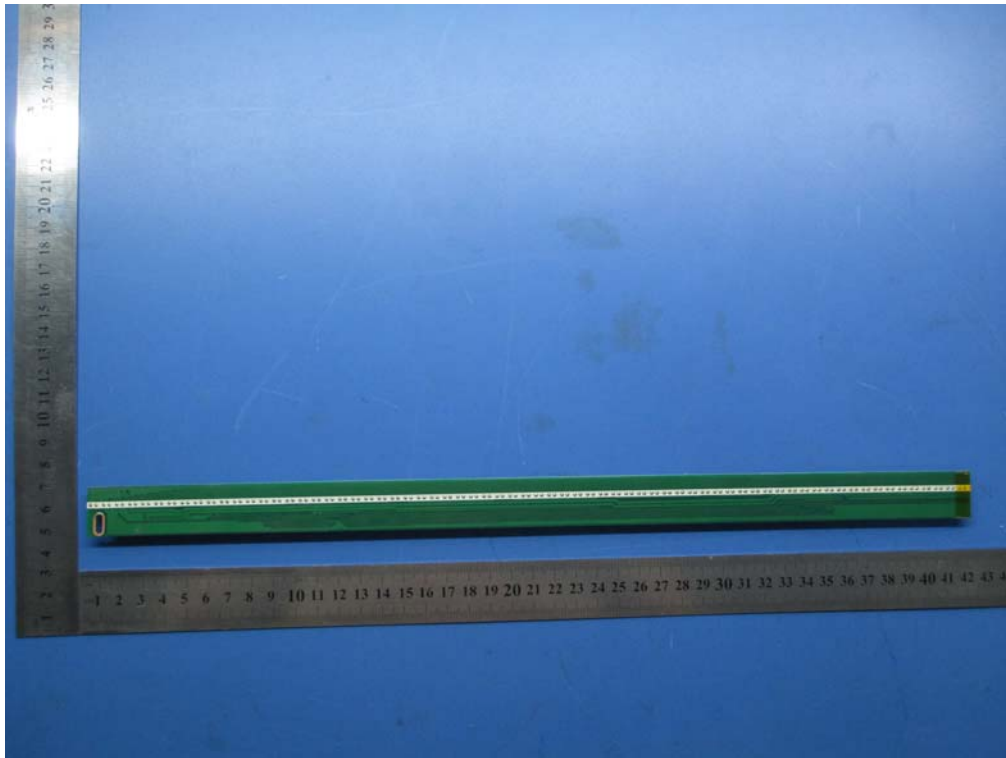
EUT PCB Board 10- Front View



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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 31 of 40
www.siemic.com.cn



EUT PCB Board 10 - Rear View



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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 32 of 40
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Annex B.iii. Photograph 3: Test Setup Photo



Conducted Emissions Test Setup Front View



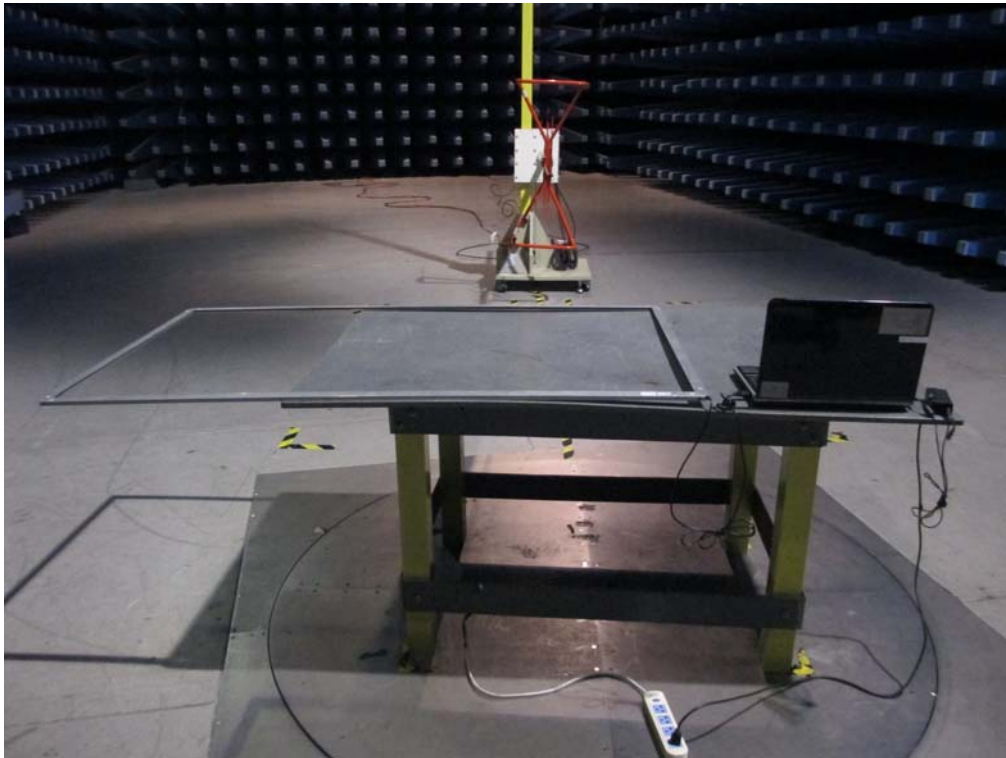
Conducted Emissions Test Setup Side View



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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 33 of 40
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Radiated Emissions Test Setup Front View



Radiated Emissions Test Setup Rear View

Annex C. TEST SETUP AND SUPPORTING EQUIPMENT

EUT TEST CONDITIONS

Annex C. i. SUPPORTING EQUIPMENT DESCRIPTION

The following is a description of supporting equipment and details of cables used with the EUT.

Equipment Description (Including Brand Name)	Model & Serial Number	Cable Description (List Length, Type & Purpose)
Gateway Laptop	MS2288 & LXWHF02013951C3CA92200	N/A

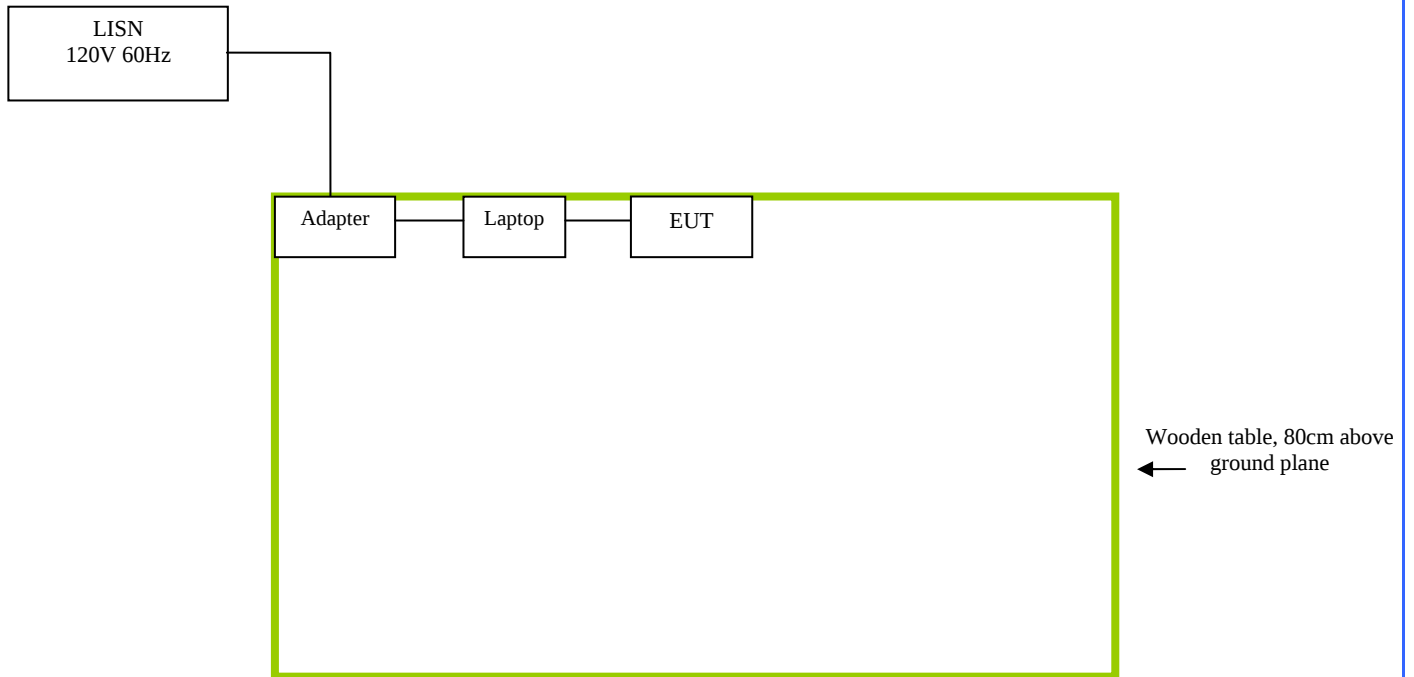


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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 35 of 40
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Block Configuration Diagram for Conducted Emissions



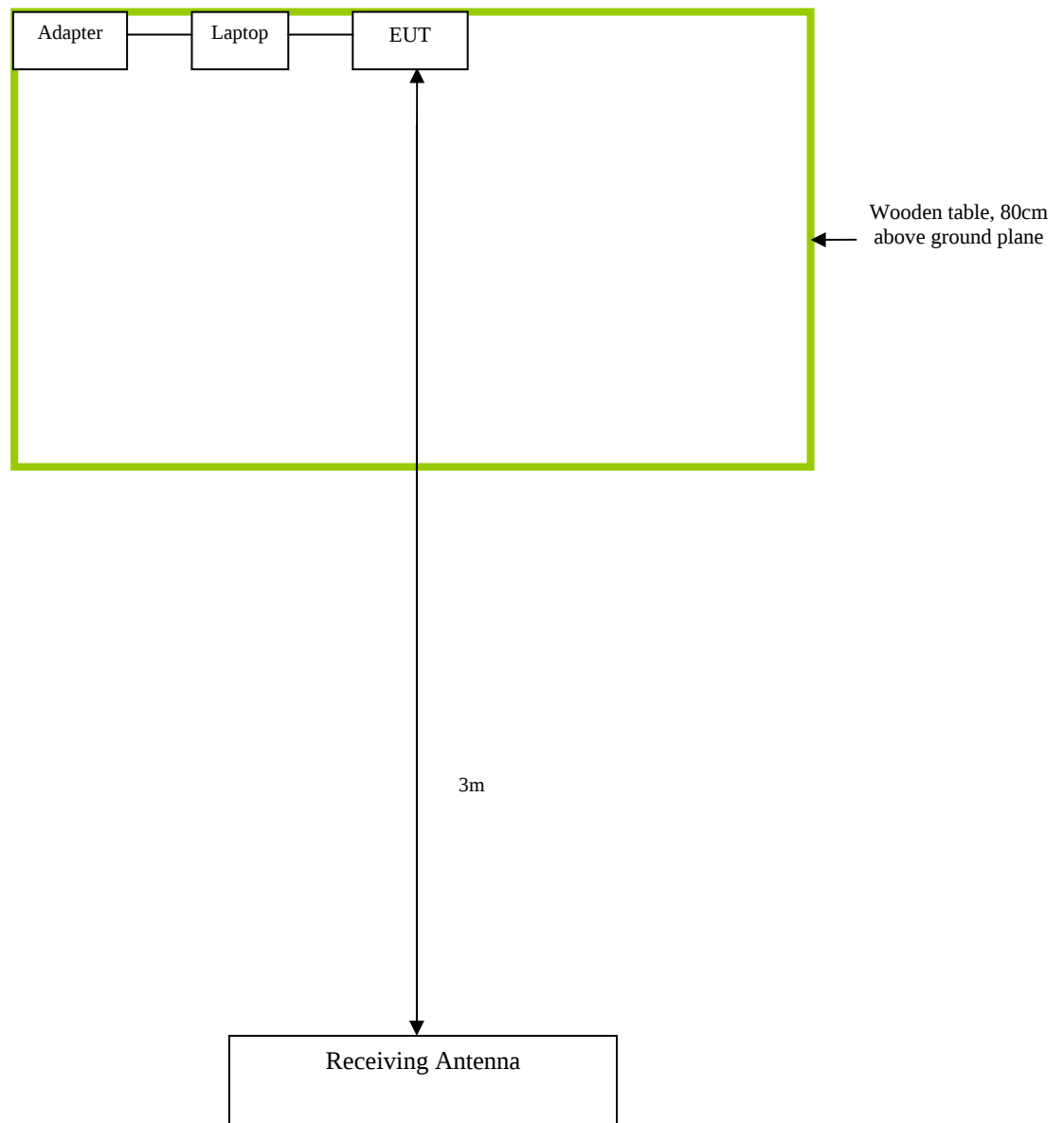


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Report No.: 13020703-FCC-E
Issue Date : November 12, 2013
Page: 36 of 40
www.siemic.com.cn

Block Configuration Diagram for Radiated Emissions



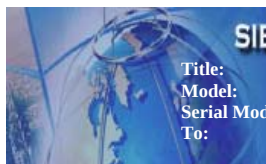
Annex C.ii. EUT OPERATING CONDITIONS

The following is the description of how the EUT is exercised during testing.

Test	Description Of Operation
Emissions Testing	Normal Working

Annex D. USER MANUAL / BLOCK DIAGRAM / SCHEMATICS / PART LIST

Please see attachment



Annex E. DECLARATION OF SIMILARITY

IRMTouch INC.

Statement

We
IRMTouch INC.

Of

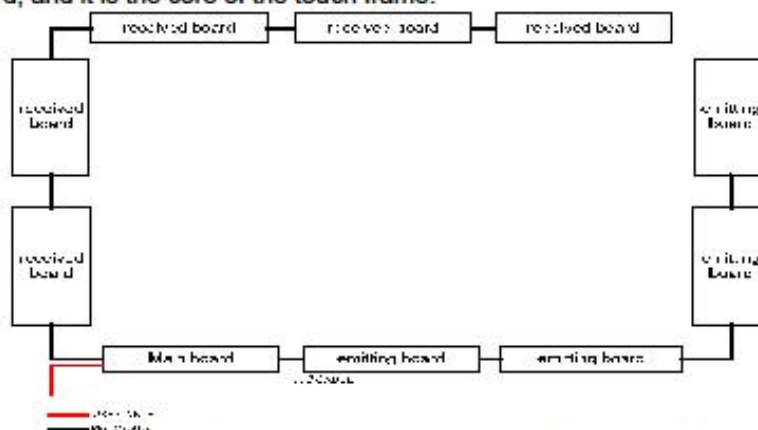
Building 5, No 445 Humin Road, Minhang, Shanghai, China
hereby state that

Product : IR Multi-Point TOUCH FRAME

Model Number : TII70-XX-N, TII65-XX-N, TII60-XX-N, TII55-XX-N, TII52-XX-N,
TII47-XX-N, TII46-XX-N, TII42-XX-N, TII37-XX-N, TII32-XX-N

All models are belongs to one product series.

The below figure is the assembly drawing of the touch frame. One touch frame is composed of mainly two kinds of PCBA, One is IR-light emitting board, and another is received board. The main board is one special IR-light emitting board, and it is the core of the touch frame.



The two kinds of PCBA is standard modular. The different models have the same constructions, circuit diagram. The difference of these models is its size, is mainly reflected in the number of received board and emitting board in different.

When we test, the tested model is the maximal size, and work under peak load.

The character "XX" is defined as the touch point number. The touch point number is related to the algorithm of software, and is not related to the circuit constructions.



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Report No.: 13020703-FCC-E
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Page: 40 of 40
www.siemic.com.cn

The last character "N" is defined as the software driver type. The character "N" means plug and play.

Sincerely,

Signature

E-mail: Liwy@irmtouch.com

Phone: 086-21-33885751

Fax: 086-21-33885752

Address: Building 5, No 445 Humin Road, Minhang, Shanghai, China